



SUPPLEMENTAL INFORMATION CITED BY APPLICANTS THAT MAY BE MATERIAL TO
THE PROSECUTION OF THE SUBJECT APPLICATION

Applicants: Y. Nakano et al.

Attorney Docket No.: NAI122545

Application No.: 10/799,786

Filed: March 12, 2004

Title: ALL-OPTICAL FLIP-FLOP

FOREIGN PATENT DOCUMENTS

*Examiner Cite Initial	Document No.	Kind Code	Publication Date (mm/dd/yyyy)	Country	English		
					Abstract Provided	Translation Provided	
/EC/	F1	JP 51-25710	B1	08/02/1976	JP		

OTHER INFORMATION
(Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner
Initial

/EC/

PTO International Search Report for PCT/JP02/09238

Examiner

Date Considered

/Erin Chiem/ (06/13/2007)

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicants.

JMS:ctg

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U.S. PATENT DOCUMENTS

*Examiner	Cite Initials	Document No.	Kind Code	Date (mm/dd/yyyy)	Name
/EC/	U1	3,439,289	A	04/15/1969	Kosonocky

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*Examiner	Cite Initial	Document No.	Kind Code	Publication Date (mm/dd/yyyy)	Country	English Abstract Provided	Translation Provided
/EC/	F4	EP 0 898 346	A1	02/24/1999	EP		
/EC/	F5	WO 96/13084	A1	05/02/1996	WO		

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/EC/	F1	JP 51-25710	A	05/21/1993	JP	X		
/EC/	F2	JP 06-13714	A	01/21/1994	JP	X	X	

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner Initial	Cite No.	Reference Description
	O1	El-Refaei, H.H., and D.A.M. Khalil, "Design of Strip-Loaded Weak-Guiding Multimode Interference Structure for an Optical Router," <i>IEEE Journal of Quantum Electronics</i> 34(12):2286-2290, December 1998.
/EC/	O2	Jian, B.B., "Continuous-Wave Operation of Monolithic Two-Mode Optical Flip-Flop With Etched Laser Mirrors," <i>Electronics Letters</i> 32(20):1923-1925, September 26, 1996.
	O3	Johnson, J.E., and C.L. Tang, "Optical Flip-Flop Based on Two-Mode Intensity Bistability in a Cross-Coupled Bistable Laser Diode," <i>Applied Physics Letters</i> 63(24):3273-3275, December 13, 1993.
/EC/	O4	Soldano, L.B., and E.C.M. Pennings, "Optical Multi-Mode Interference Devices Based on Self-Imaging: Principles and Applications," <i>Journal of Lightwave Technology</i> 13(4):615-627, April 1995.
	O5	Soldano, L.B., et al., "Planar Monomode Optical Couplers Based on Multimode Interference Effects," <i>Journal of Lightwave Technology</i> 10(12):1843-1850, December 1992.
/EC/	O6	Watanabe, M., "Bistability Between Two Crosscoupled Lateral Modes in Twin-Stripe Lasers," <i>Bulletin of the Electrotechnical Laboratory</i> 57(11):69-77, November 1993.

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07 Watanabe, M., et al., "An Optical Set-Reset Flip-Flop Semiconductor Laser With Two Mutually Complementary Outputs," *Proceedings of the International Conference on Optical Computing*, Edinburgh, U.K., August 22-24, 1994, pp. 581-584.

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